



ALPHA & OMEGA
SEMICONDUCTOR

AO6608

20V Complementary MOSFET

General Description

The AO6608 combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$. This device is ideal for load switch and battery protection applications.

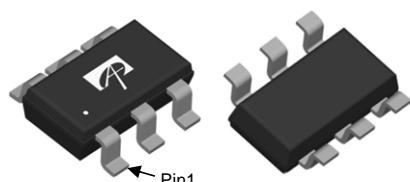
- RoHS and Halogen-Free Compliant

Product Summary

N-Channel	P-Channel
$V_{DS} = 30V$	-20V
$ID = 3.4A$ ($V_{GS}=10V$)	-3.3A ($V_{GS}=-4.5V$)
$R_{DS(ON)}$	$R_{DS(ON)}$
< 60mΩ ($V_{GS}=10V$)	< 75mΩ ($V_{GS}=-4.5V$)
< 70mΩ ($V_{GS}=4.5V$)	< 105mΩ ($V_{GS}=-2.5V$)
< 90mΩ ($V_{GS}=2.5V$)	< 135mΩ ($V_{GS}=-1.8V$)

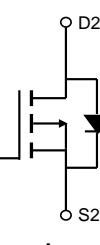
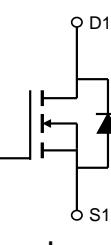
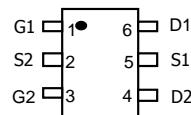


Top View



Bottom View

Top View



n-channel p-channel

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Max n-channel	Max p-channel	Units
Drain-Source Voltage	V_{DS}	30	-20	V
Gate-Source Voltage	V_{GS}	± 12	± 8	V
Continuous Drain Current	I_D	3.4	-3.3	A
Current		2.7	-2.5	
Pulsed Drain Current ^C	I_{DM}	20	-13	
Power Dissipation ^B	P_D	1.25	1.25	W
		0.80	0.80	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150		°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	75	100	°C/W
Maximum Junction-to-Ambient ^{A,D}		105	130	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	50	65	°C/W

N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$			± 100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.5	1	1.5	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=3.4\text{A}$ $T_J=125^\circ\text{C}$		46	60	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=3\text{A}$		50	70	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}, I_D=2\text{A}$		62	90	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=3.4\text{A}$		14		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.75	1	V
I_S	Maximum Body-Diode Continuous Current				1.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		235		pF
C_{oss}	Output Capacitance			35		pF
C_{rss}	Reverse Transfer Capacitance			18		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	0.9	1.8	2.7	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=3.4\text{A}$		6	10	nC
$Q_g(4.5\text{V})$	Total Gate Charge			3		nC
Q_{gs}	Gate Source Charge			0.55		nC
Q_{gd}	Gate Drain Charge			0.8		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, RL=4.4\Omega, RGEN=3\Omega$		1.5		ns
t_r	Turn-On Rise Time			2.5		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			16		ns
t_f	Turn-Off Fall Time			2		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=3.4\text{A}, dI/dt=100\text{A}/\mu\text{s}$		6		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=3.4\text{A}, dI/dt=100\text{A}/\mu\text{s}$		1.2		nC

A. The value of R_{0JA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

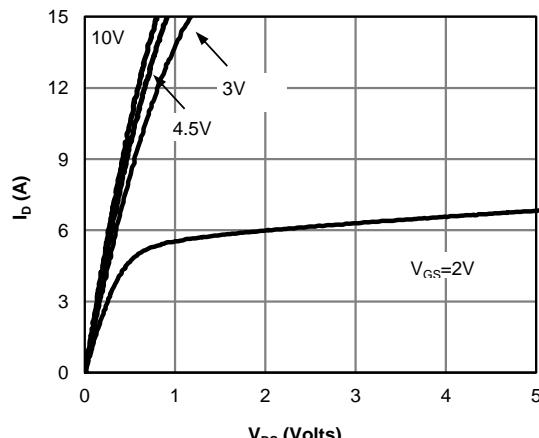
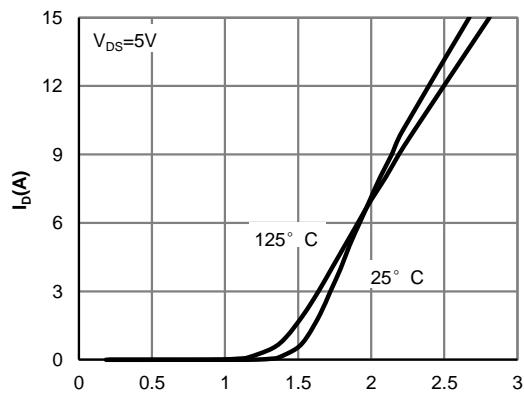
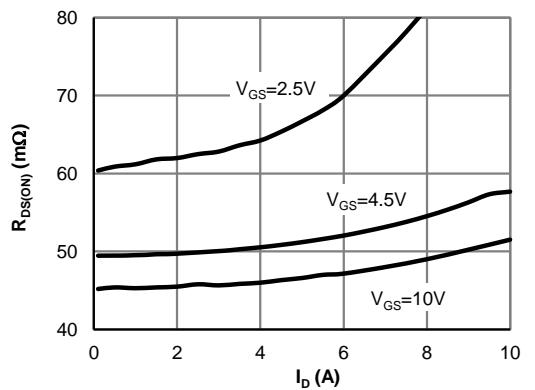
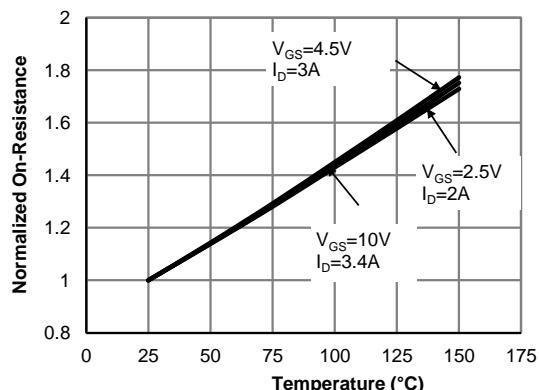
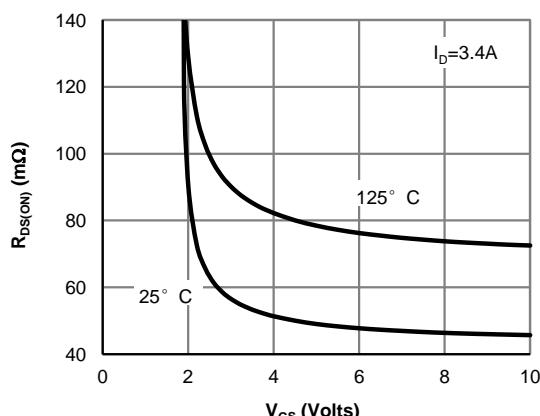
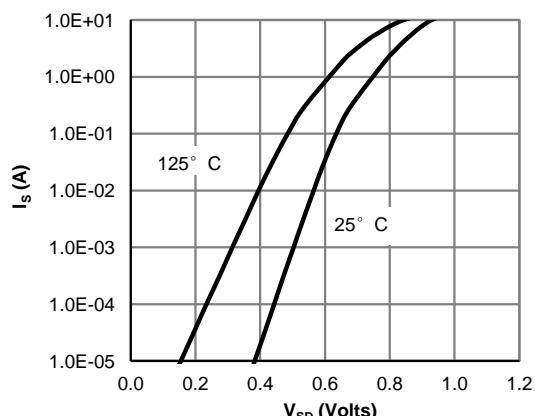
C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

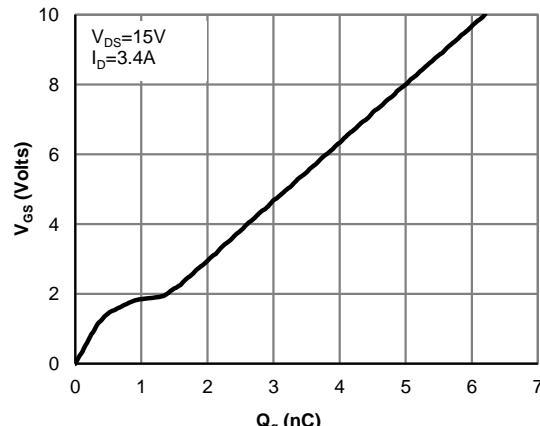
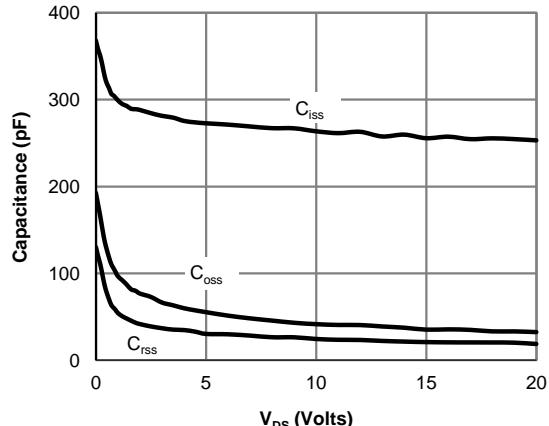
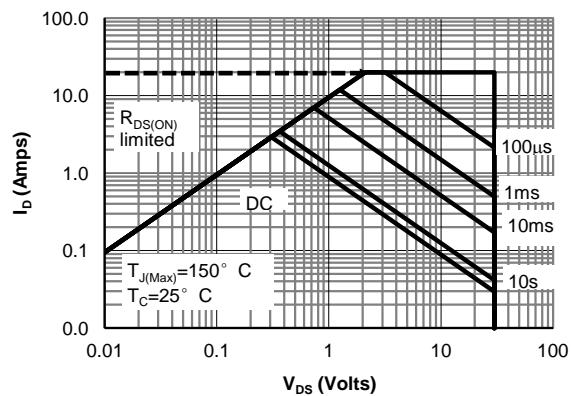
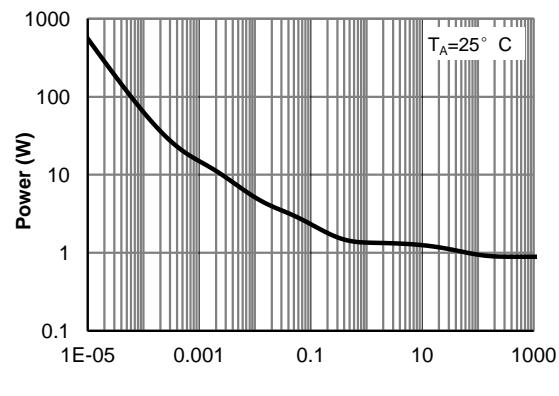
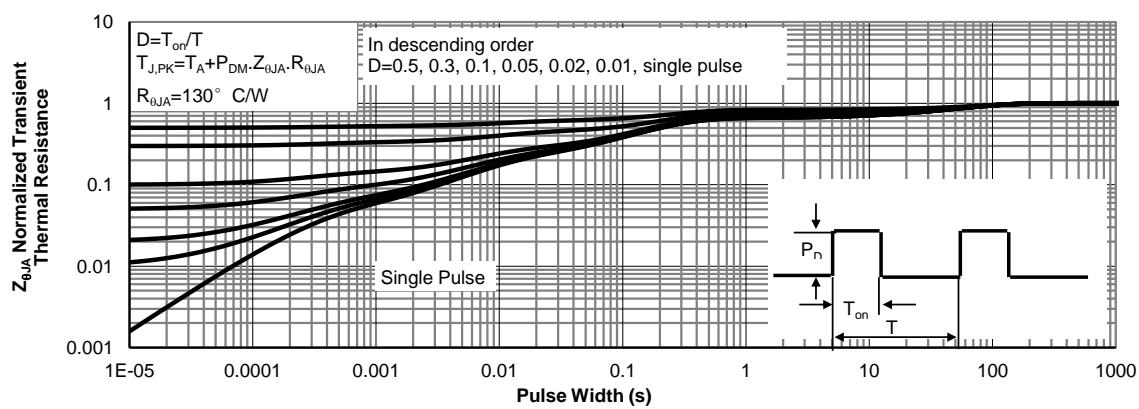
D. The R_{0JA} is the sum of the thermal impedance from junction to lead R_{0JL} and lead to ambient.

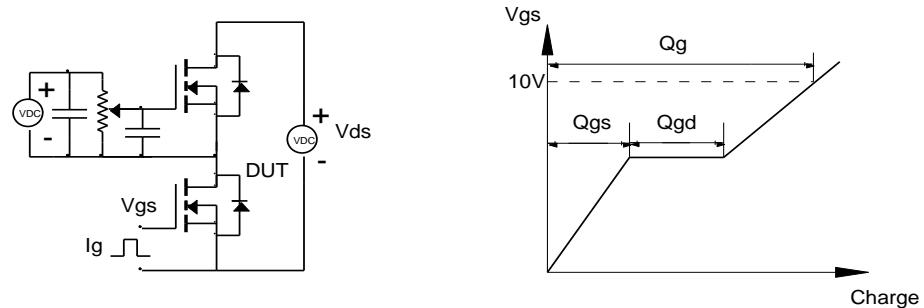
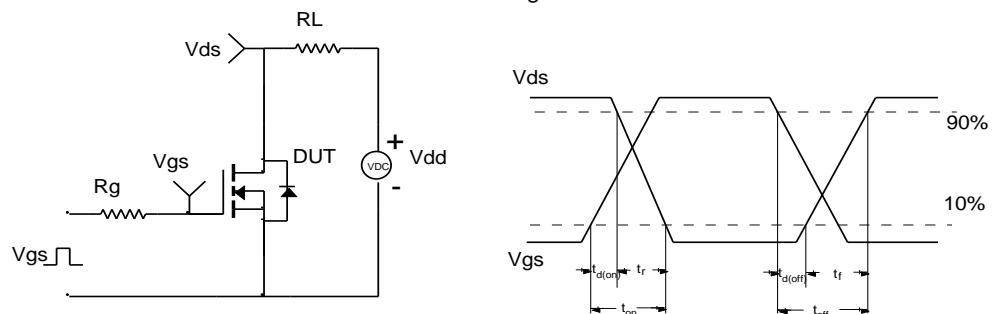
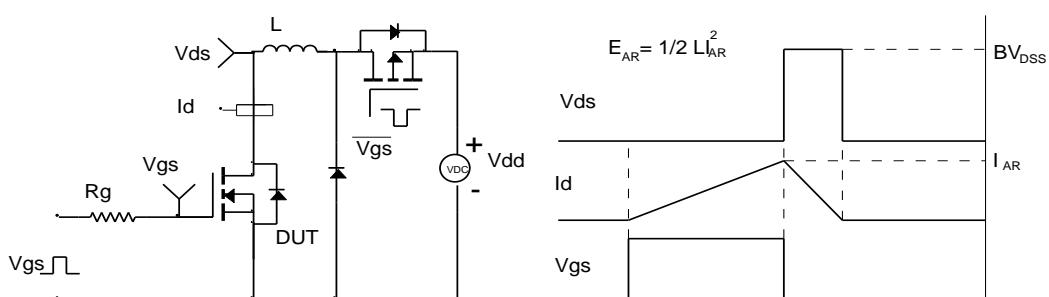
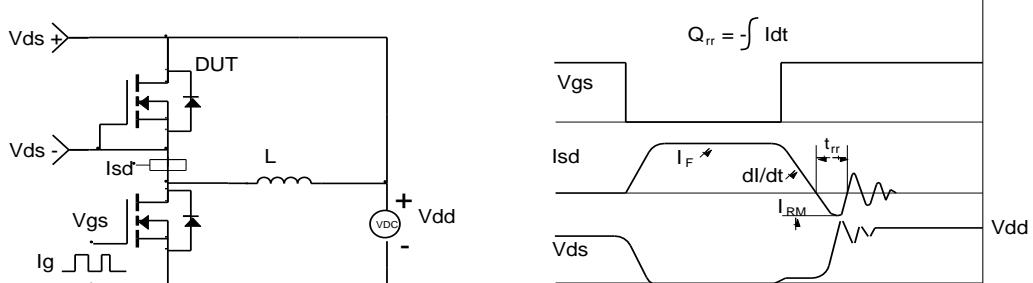
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

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N-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

N-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms


P-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-20\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		-1	-5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 8\text{V}$			± 100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.4	-0.65	-1	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5\text{V}, I_D=-3.3\text{A}$ $T_J=125^\circ\text{C}$	63	75		$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}, I_D=-2.5\text{A}$	78	105		$\text{m}\Omega$
		$V_{GS}=-1.8\text{V}, I_D=-1\text{A}$	96	135		$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-3.3\text{A}$	13			S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.7	-1	V
I_S	Maximum Body-Diode Continuous Current				-1.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-10\text{V}, f=1\text{MHz}$		510		pF
C_{oss}	Output Capacitance		70			pF
C_{rss}	Reverse Transfer Capacitance		50			pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	15	30		Ω
SWITCHING PARAMETERS						
$Q_g(4.5\text{V})$	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, I_D=-3.3\text{A}$		6	10	nC
Q_{gs}	Gate Source Charge		0.6			nC
Q_{gd}	Gate Drain Charge		1.8			nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, R_L=4\Omega, R_{\text{GEN}}=6\Omega$	11			ns
t_r	Turn-On Rise Time		11			ns
$t_{D(\text{off})}$	Turn-Off DelayTime		60			ns
t_f	Turn-Off Fall Time		30			ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-3.3\text{A}, dI/dt=100\text{A}/\mu\text{s}$	16			ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-3.3\text{A}, dI/dt=100\text{A}/\mu\text{s}$	4			nC

A. The value of R_{iJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

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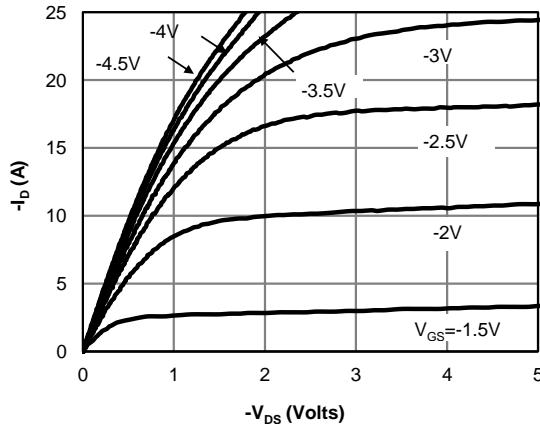
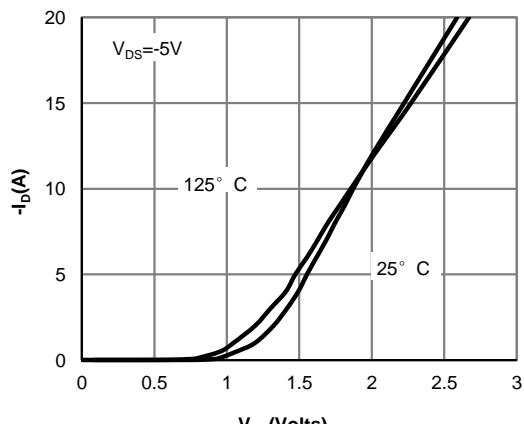
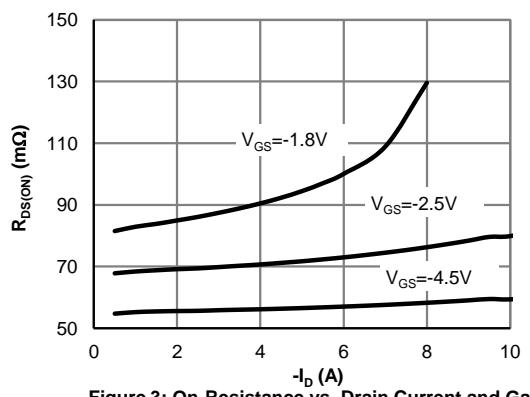
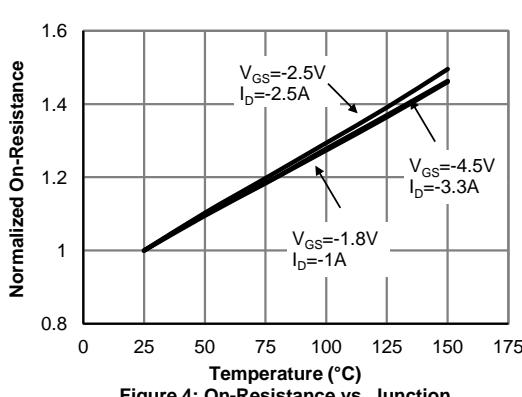
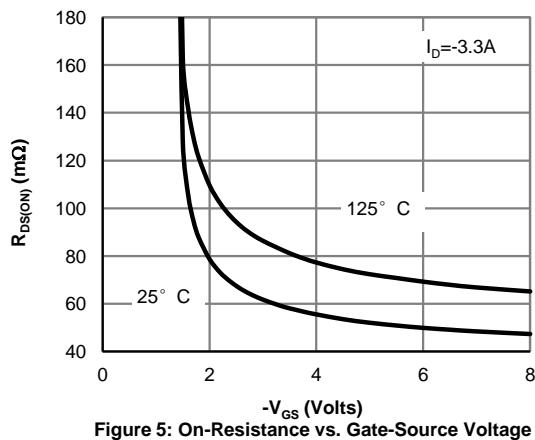
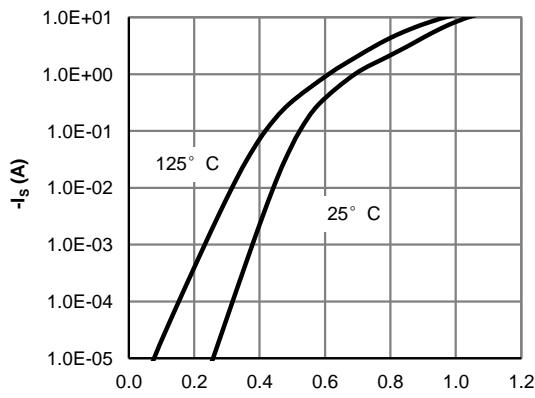
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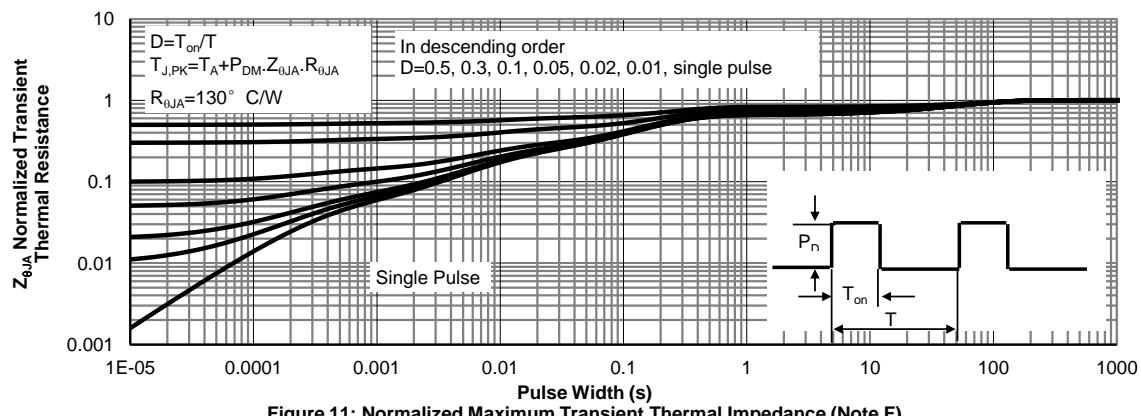
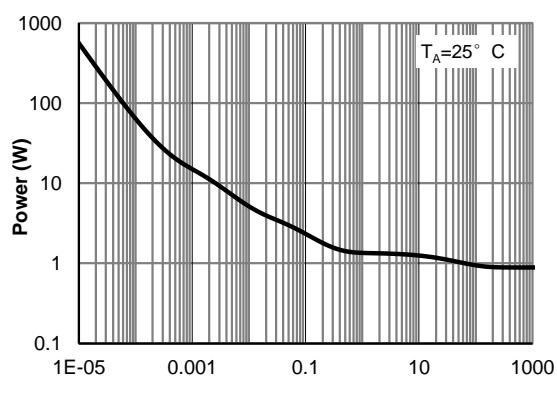
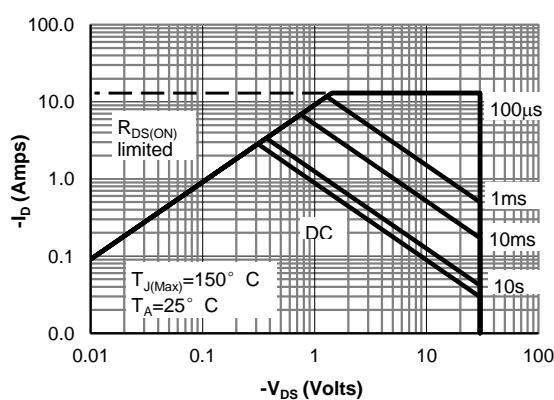
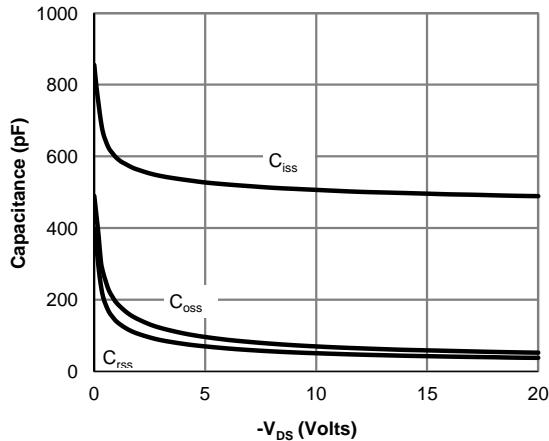
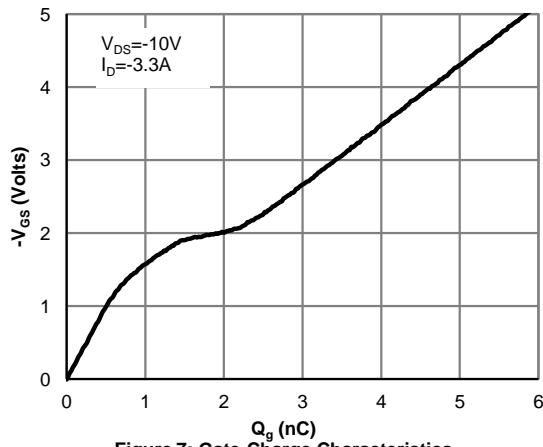
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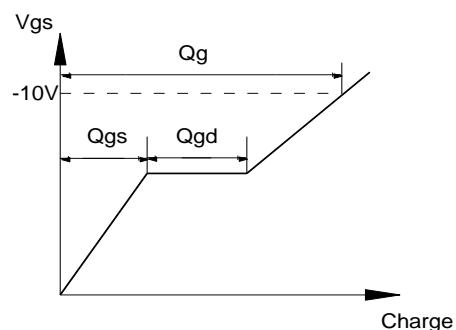
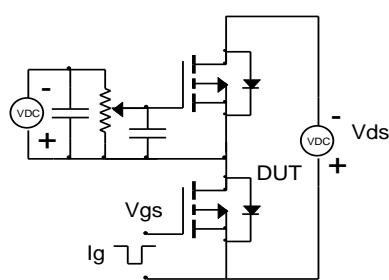
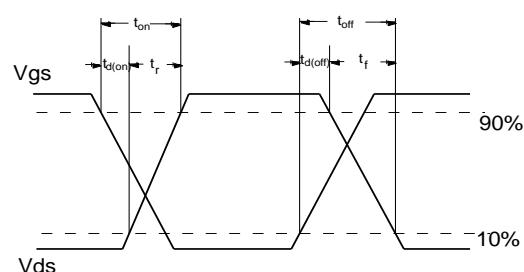
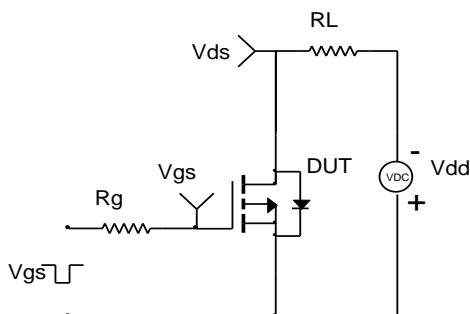
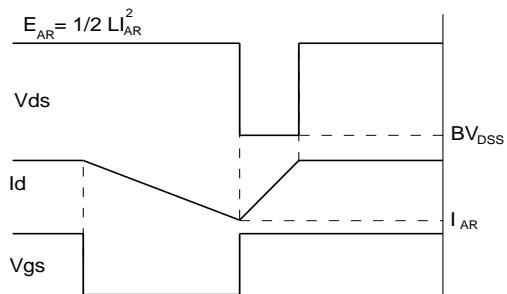
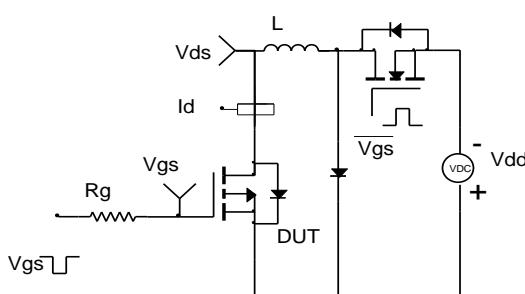
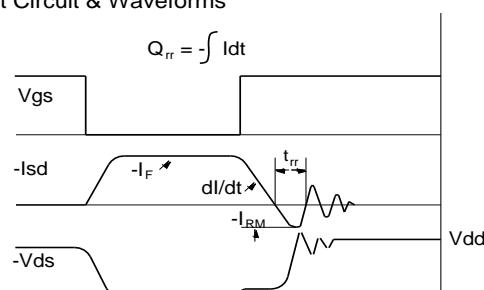
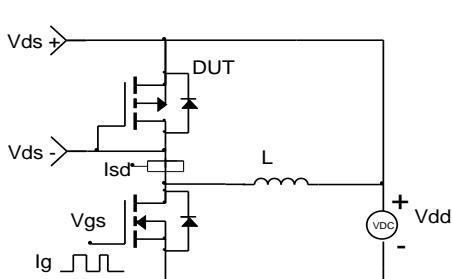
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Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms


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